Test Week 2016 At-a-Glance

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| **SUNDAY, NOVEMBER 13 – HALF-DAY TUTORIALS** |
| **Room** | **201A** | **201B** | **201C** |
| **8:30 a.m. – 12:00 p.m.** | Tutorial1Testing of TSV-based 2.5D- and 3D-Stacked ICs | Tutorial 2From Data to Actions: Application of Data Analytics in Semiconductor Manufacturing and Test | Tutorial 3Test Opportunities and Challenges for Secure Hardware and Verifying Trust in Integrated Circuits |
| **1:00 p.m. – 4:30 p.m.** | Tutorial 4Testing of Automotive ICs: introduction and Advances | Tutorial 5Diagnosis-driven Yield Analysis | Tutorial 6Targeting "Zero Defect" IC Quality: Advanced Cell-aware Fault Models and Adaptive Test |

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| **MONDAY, NOVEMBER 14 – HALF-DAY TUTORIALS** |
| **Room** | **201A** | **201B** | **201C** |
| **8:30 a.m. – 12:00 p.m.** | Tutorial 7Memory Test and Repair in the FinFet Era | Tutorial 8Test, Diagnosis, and Root-Cause Identification of Failures for Boards and Systems | Tutorial 9Mixed-Signal DFT and BIST: Trends, Principles and Solutions |
| **1:00 p.m. – 4:30 p.m.** | Tutorial10Automotive Reliability and Test Strategies | Tutorial 11Combining Structural and Functional Test Approaches Across System Levels | Tutorial12Practices in High-Speed I/O Testing |

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| **MONDAY, NOVEMBER 14 – PANEL** |
| **4:45 p.m. – 6:30 p.m**. | Panel 1 The Unknown Unknowns of Test.203A/B/C |

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| **MONDAY, NOVEMBER 14 – POST-PANEL RECEPTION** |
| **6:30 p.m. – 8:00 p.m**. | Post-Panel Reception/Social **Belt Buckle Lobby of the Ft. Worth Convention Center** |

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| **TUESDAY, NOVEMBER 15 – TECHNICAL SESSIONS** |
| **9:00 a.m. – 10:30 a.m.** | Plenary – Keynote Address  *The Business of Test:  Test and Semiconductor Economics,* Walden C. Rhines **Ballroom A/B** |
| **10:30 a.m. – 5:30 p.m.** | Exhibits  **Exhibit Hall**  |
| **11:00 a.m. – 2:00 p.m.** | Corporate Forum  **Exhibit Hall**  |
| **12:00 p.m. – 2:00 p.m.** | Lunch **Exhibit Hall**  |
| **Room** | **201A** | **201B** | **201C** | **202A** | **202B** |
| **2:00 p.m. – 4:00 p.m.** | Session 1 Diagnosis | Session 2 DFT | Poster Preview Talks | Special Session 1 Test of Low/High-Power Devices | IEEE TTTC E. J. McCluskey Best Doctoral Thesis Award: Final Round |
| **4:30 p.m. – 6:00 p.m.** | Special Session 3Test for Security and Trust | Panel 2 Phased Array 5G:Is Test Connected or Disconnected? | Panel 3Test Cost Reduction —Is There More to Cut? | Special Session 23D-IC Test Standard IEEE P1838 | Embedded Tutorial 1Diagnosis to Failure Isolation: The Journey to Root Cause |

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| **TUESDAY, NOVEMBER 15 – ITC WELCOME RECEPTION** |
| **6:30 p.m. –8:30 p.m**. | ITC Welcome Reception **Ashton Depot** |

Test Week 2016 At-a-Glance

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| **WEDNESDAY, NOVEMBER 16– TECHNICAL SESSIONS** |
| **Room** | **201A** | **201B** | **201C** | **202A** | **202B** |
| **8:30 a.m.–10:00 a.m.** | Session 3Analog I | Session 4Memory | Session 5Analytics I | Special Session 4IEEE 1687.1: What, Why and How | Special Session 5mmWave ATE HVM Technology |
| **9:30 a.m.–4:30 p.m.** | Exhibits **Exhibit Hall** |
| **10:30a.m.–12:00 p.m.** | Session 6IEEE 1687  | Session 9Emerging Devices | Session 7Analog II | Session 8Analytics II | Special Session 6Heterogeneous Integration Pushes the Test Roadmap |
| **12:00 p.m.–2:00p.m.** | Poster Session – Lunch **Exhibit Hall**  |
| **12:00 p.m.–2:00 p.m.** | Corporate Forum **Exhibit Hall** |
| **2:00 p.m.–3:30 p.m.** | Session 10Test Vehicle Design | Session 11ATE I | Session 12Security  | Session 13Methodology | Special Session 7Design, Test and Reliability of STT-MRAM |
| **4:30 p.m.–5:45 p.m.** | Keynote Address in honor of E. J. McCluskey *Hardware Inference Accelerators for Machine Learning* Rob A. Rutenbar **Ballroom A/B** |

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| **THURSDAY, NOVEMBER 17 – TECHNICAL SESSIONS** |
| **Room** | **201A** | **201B** | **201C** | **202A** | **202B** |
| **9:00 a.m.–10:30 a.m.** | Session 14ATE II | Session 15Reliability | Session 16Test Generation | Special Session 8Automotive IC Quality & Reliability: Today’s Challenges and Solutions |  |
| **9:30 a.m. – 1:30 p.m.**  | Exhibits **Exhibit Hall** |
| **11:00 a.m.–12:00 p.m.** | [Keynote Address](#Keynote_Thur) *Addressing Semiconductor Industry Needs: Defining the Future Through Creative, Exciting Research* Ken Hansen**Ballroom A/B****Disneyland Grand Ballroom Center***Design and Modeling Challenges* |
| **12:00 p.m.– 1:30 p.m.** | Lunch **Exhibit Hall**  |
| **1:30 p.m.– 3:00 p.m.** | Session 17Mixed-Signal | Session 18Practices | Panel 4ATE Revisited – Where Are We Today and Where Should We Be Heading? | Embedded Tutorial 2ISO 26262 | Panel 5 Test, Validation and Security for IoTs |

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| **THURSDAY, NOVEMBER 17 – WORKSHOPS** |
| **Room** | **201A** | **201C** |
| **4:00 p.m. – 4:30 p.m.** | Opening Address | Opening Address |
| **4:30 p.m. – 6:30 p.m.** | Automotive Reliability and Test | Defects, Adaptive Test and Data Analysis |
|  **7:00 p.m. – 9:00 p.m.** | Workshop Reception Belt Buckle Lobby of the Ft. Worth Convention Center |

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| **FRIDAY, NOVEMBER 18 – WORKSHOPS** |
| **Room** | **201A** | **201C** |
| **8:00 a.m. – 4:00 p.m.** | Automotive Reliability and Test | Defects, Adaptive Test and Data Analysis |